Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/767,770	OGAWA, HIDEHIKO	
Examiner	Art Unit	
Thomas D. Lee	2625	

SEARCHED					
Class	Subclass	Date	Examiner		
358	1.15, 402, 440	9/28/2005	TDL		
379	100.01	9/28/2005	TDL		
379	100.08	9/28/2005	TDL		
379	100.13	9/28/2005	TDL		
379	100.17	9/28/2005	TDL		
updated		3/31/2006	TDL		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	l			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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